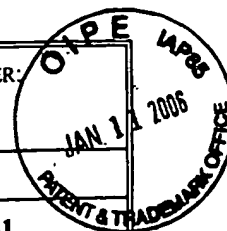


Form PTO 1449 & PTO/SB/08B Reference Documents submitted prior to action on merits in RCE, 11-Jan-2006	ATTY. DOCKET NUMBER: UKRF-120RCE	PATENT APPLICATION NUMBER: 10/827,176
U.S. Patent & Trademark Office	APPLICANT(S): C. Jaynes, Ph.D. and D. Ramakrishnan	
Information Disclosure Statement of both US & non-US patent refs	FILING DATE: 19 April 2004 {PROV. APP. FILED: April 2003}	GROUP ART UNIT: 2851 Examiner: KOVAL, Melissa J.



U.S. Patent Documents & published U.S. patent apps. (listing submitted on-line: <none>)

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)
MSK	US-2002/63807-A1	30-May-2002	Margulis, Neal	348	745	
	US2002/0063807					

Other Documents—listed for reference, a copy of each item listed is enclosed.**

EXAMINER INITIAL	DOCUMENT DETAILS
MSK	M. ELAD and A. FEUER, "Restoration of Single Super-Resolution Image from Several Blurred, Noisy and Under Sampled Measured Images," <i>IEEE Transactions on Image Processing</i> , vol. 6, no. 12, pp. 1646-58 (December 1997); {labeled "ATTACHMENT C" of applicants' provisional app. filed in April 2003 as background information}
MSK	A. MAJUMDER and G. WELCH, "Computer Graphics Optique: Optical Superposition of Projected Computer Graphics," <i>Fifth Immersive Projection Technology Workshop, Seventh Eurographics Workshop on Virtual Environments</i> , Stuttgart, Germany Springer-Verlag (May 2001) 8 pages {labeled "ATTACHMENT D" of applicants' provisional app. filed in April 2003}
MSK	S. BAKER and T. KANADE, "Limits on Super-Resolution and How to Break Them," <i>Int. Conf. Computer Vision & Pattern Recognition</i> , Vol. 2 (2000) pp. 372-379; {labeled "ATTACHMENT E" of applicants' provisional app. filed in April 2003}
MSK	R. STEELE and Christopher JAYNES, "Monitoring and Correction of Geometric Distortion in Projected Displays," <i>Central European Conference on Computer Graphics and Computer Vision</i> , (04 -08 February 2002) {labeled "ATTACHMENT G" of applicants' provisional app. filed in April 2003}
Examiner:	Date Considered: 7/14/06

EXAMINER: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.